

## Search Notes



Application No.

10/608,883

Examiner

Stephen W. Smoot

Applicant(s)

AVANZINO ET AL.

Art Unit

2813

## SEARCHED

Class	Subclass	Date	Examiner
257	751	5/25/2004	SWS
257	752	5/25/2004	SWS
257	759	5/25/2004	SWS
257	760	5/25/2004	SWS
257	762	5/25/2004	SWS
Updated	Above	11/5/2004	SWS
Updated	Above	4/26/2005	SWS

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Considered all citations from parent applications.	5/25/2004	S.W.S.
Key Words: Damascene Structure - Inlaid, Copper, Electroplated, Seed Layer;	5/25/2004	S.W.S.
Interlayer Dielectric - SiCOH, MSQ; Insulating Barrier - SiCH.	5/25/2004	S.W.S.
Updated Above Search	11/5/2004	S.W.S.
Updated Above Search	4/26/2005	S.W.S.
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	5/25/2004; 11-5-04; 8 4-26-04	S.W.S.